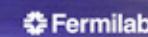
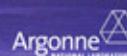




15th International Conference on RF Superconductivity

**July 25-29, 2011**

Sheraton Chicago Hotel & Towers



# Sources of Quench Producing Defects Low and High Fields

Rong-Li Geng

Jefferson Lab



**U.S. DEPARTMENT OF  
ENERGY**



**Jefferson Lab**



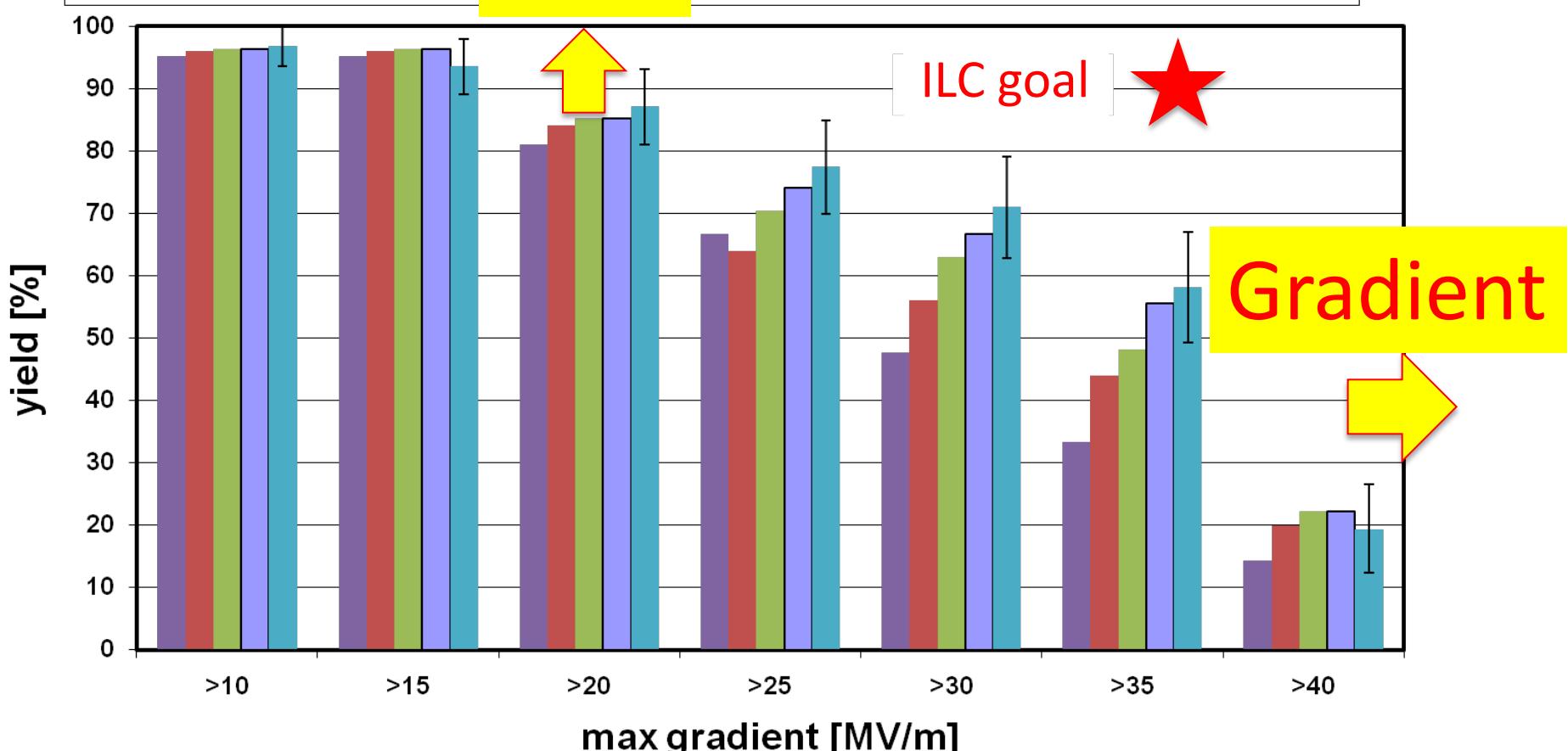
1 meter

International Linear Collider (ILC)  
16000 cavities, each 1 square-meter surface area  
Operation temperature 2 Kelvin

Electropolished 9-cell cavities  
JLab/DESY (combined) 10-second successful test of  
cavities from established vendors

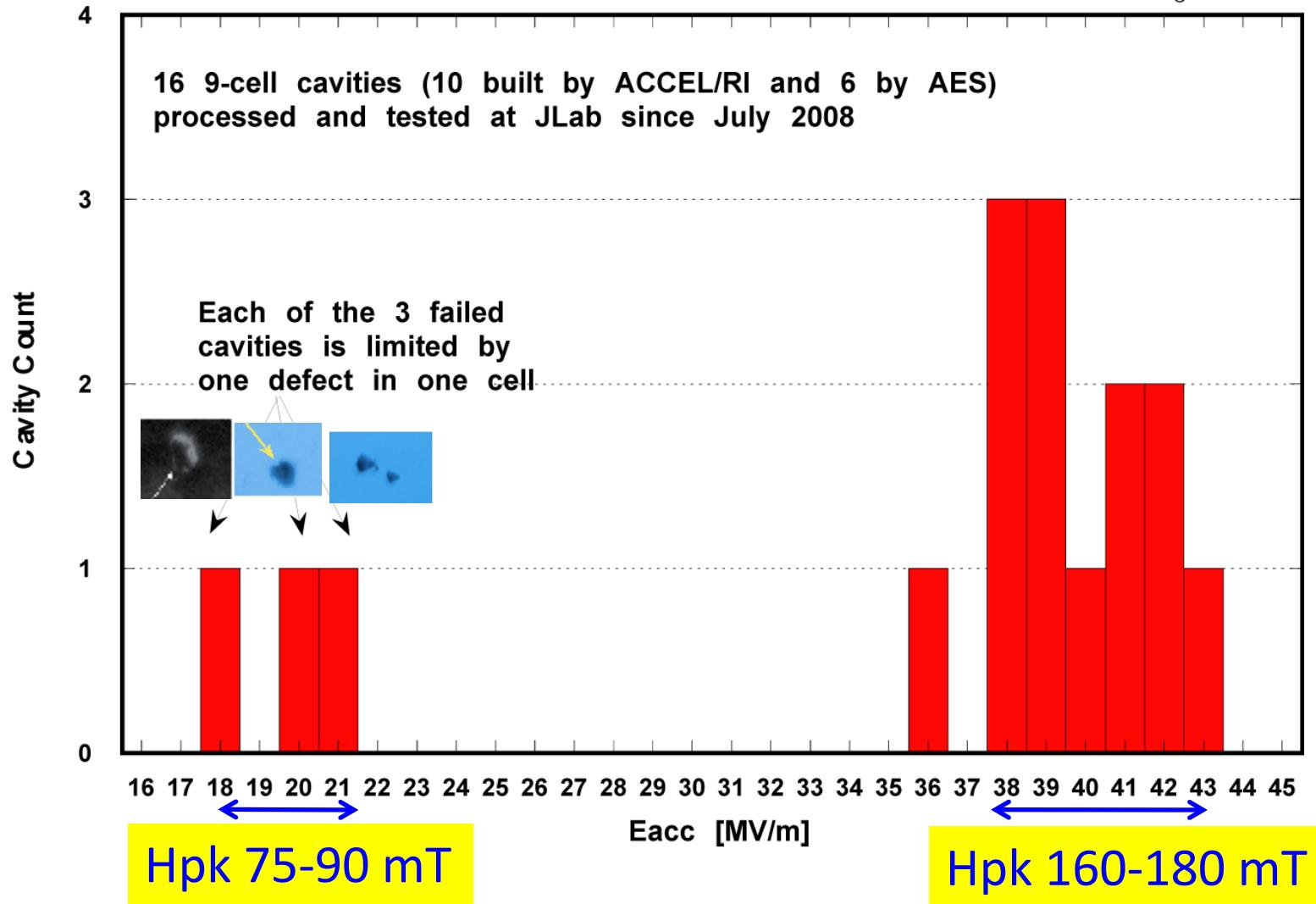
**Yield**

ALCPG 1.Oct.2009 AAP 6.Jan.2010 28.Mar.2010 TDP Rev.5 30.Jun.2010 ALCPG 20.Mar.2011



## Gradient Scatter (up to 2nd-pass proc.)

RLGeng19oct10

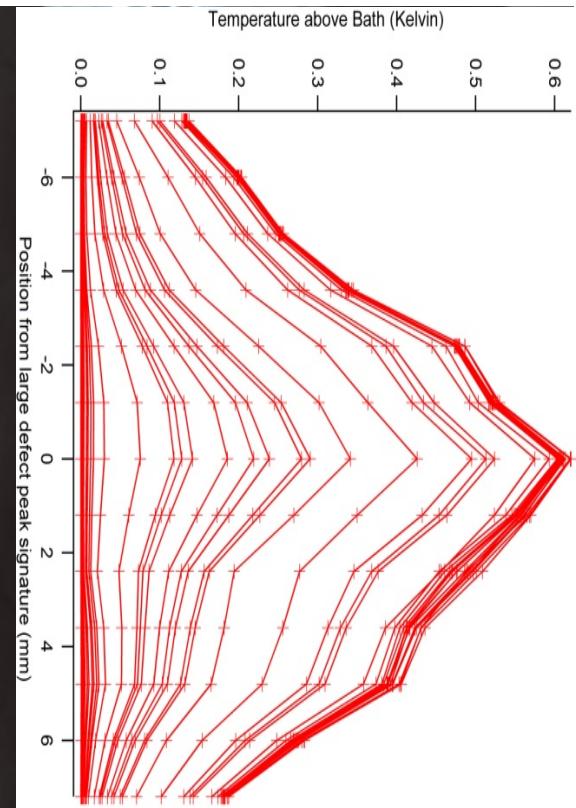
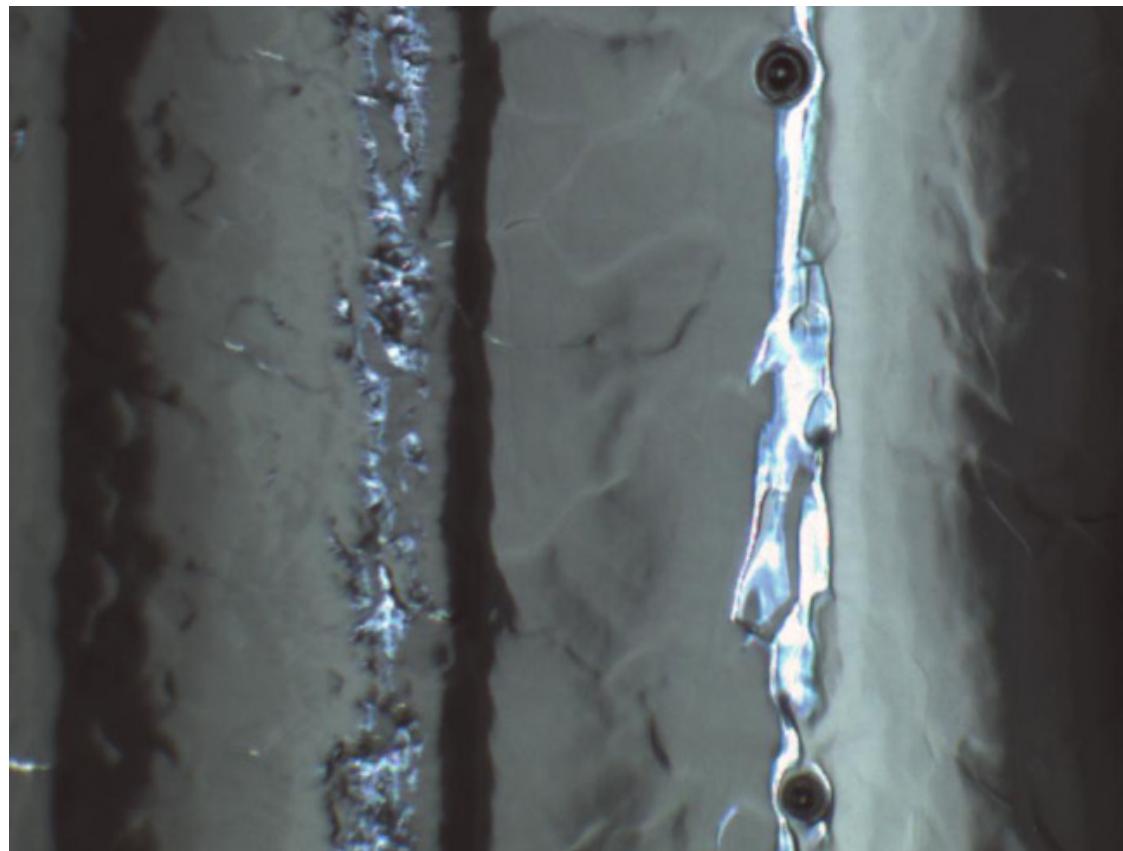
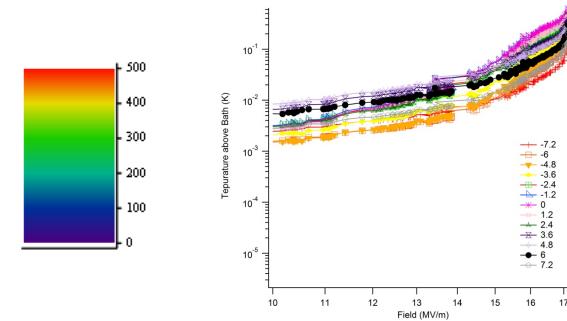
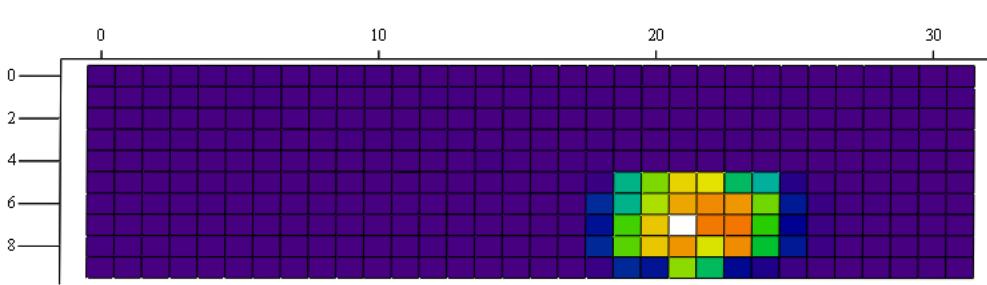


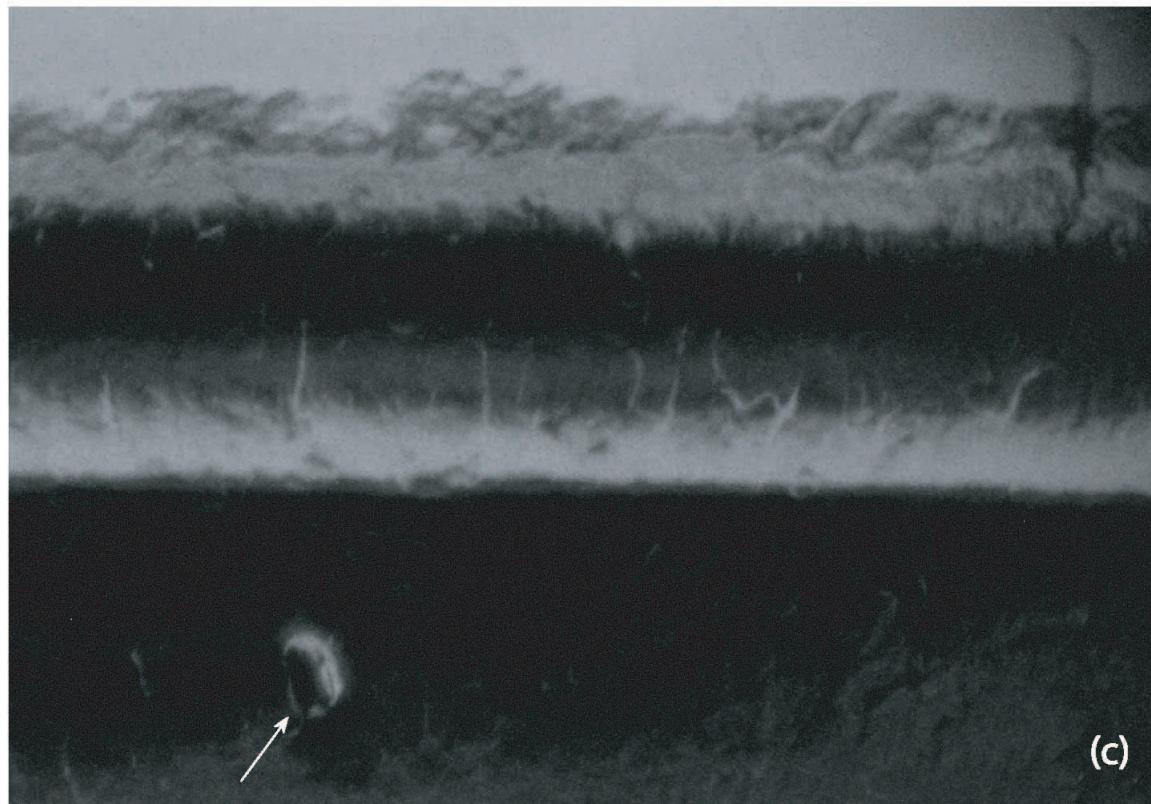
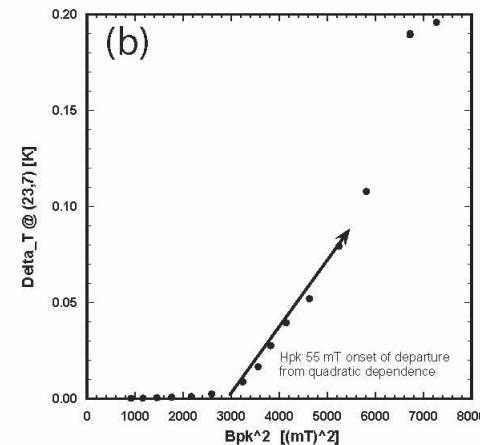
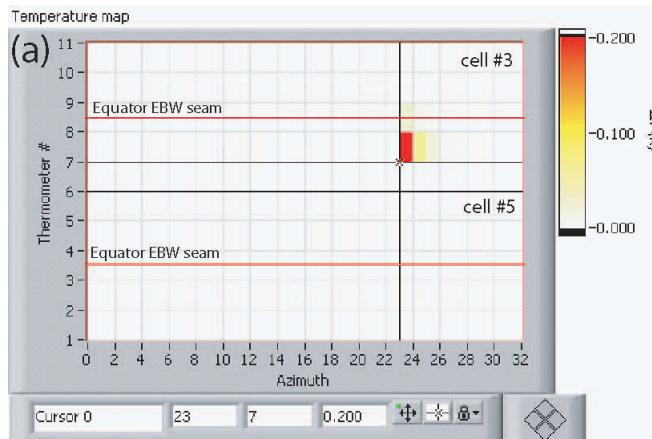
# Two Types of Quench (Defect)

- Type-I
  - Hpk 75-90 mT
  - Defect from fabrication
    - Near or in EBW joint
    - Geometric defects
    - Sum-mm in size
      - Observable with “high-resolution” optical inspection machine
    - Little effect by repeated surface processing
    - Mechanical (local or global) polishing effective

# Two Types of Quench

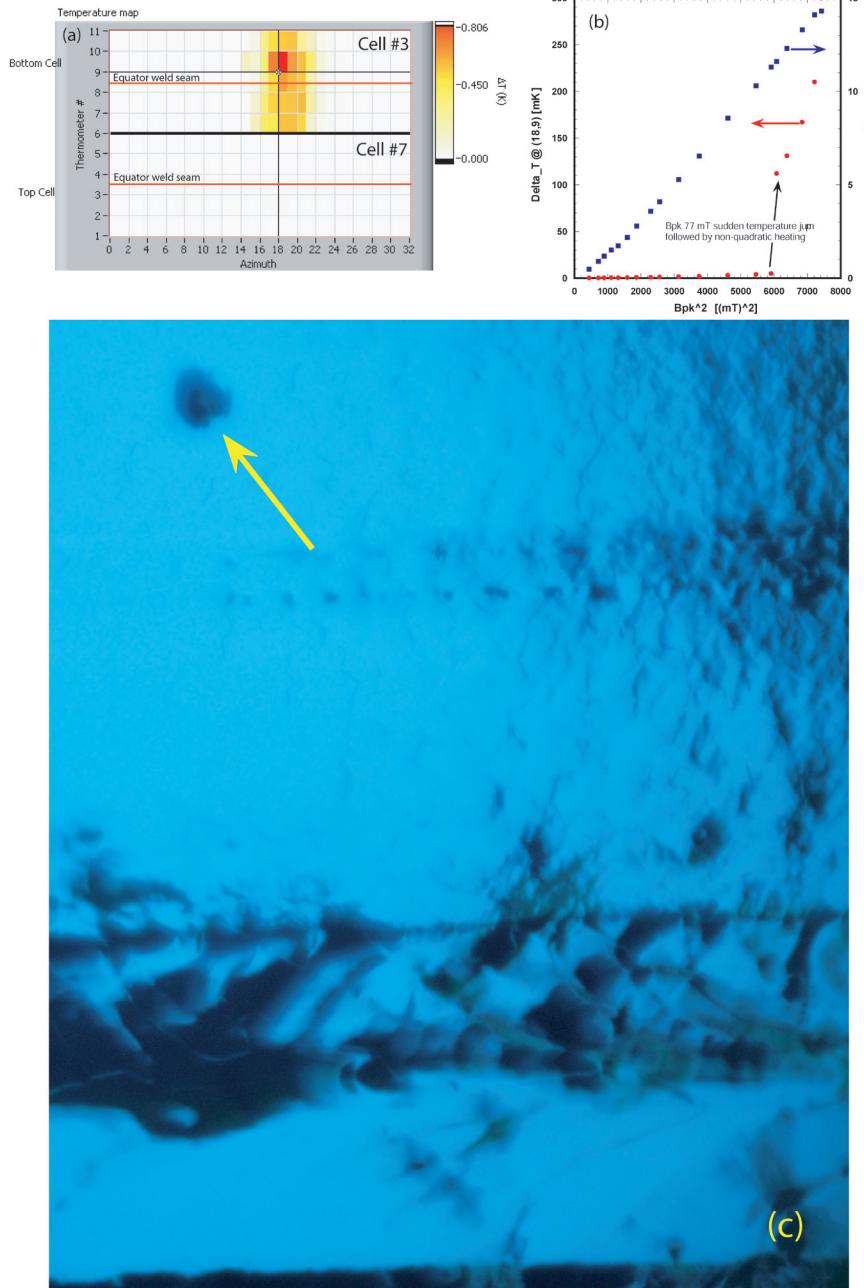
- Type-II
  - $H_{pk} > 1100$  Oe
  - Nature of defect not well understood
    - Still near EBW weld (high magnetic field region)
    - Size unknown
      - Not observable with “high-resolution” optical inspection machine
    - Re-EP is found often times effective
      - Raise limit to  $> H_{pk} 1500$  Oe





Fine grain EP  
defect causing  
quench 19 MV/m.

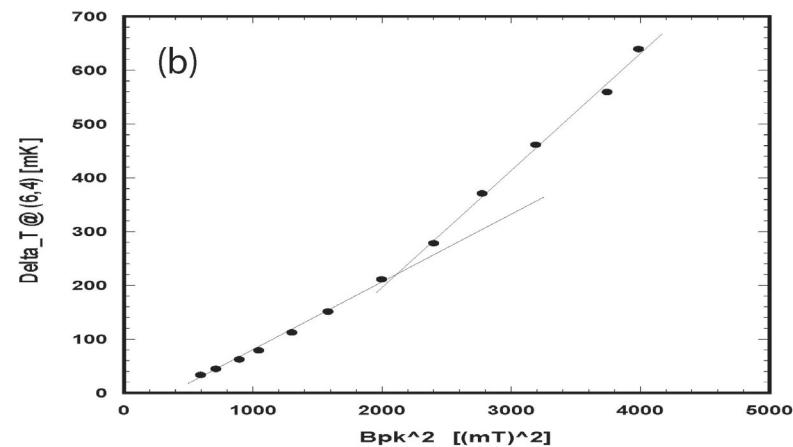
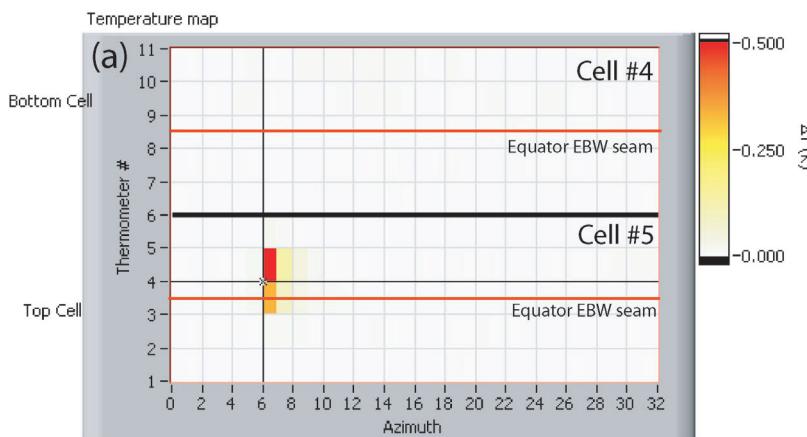
Cavity by  
experience vendor



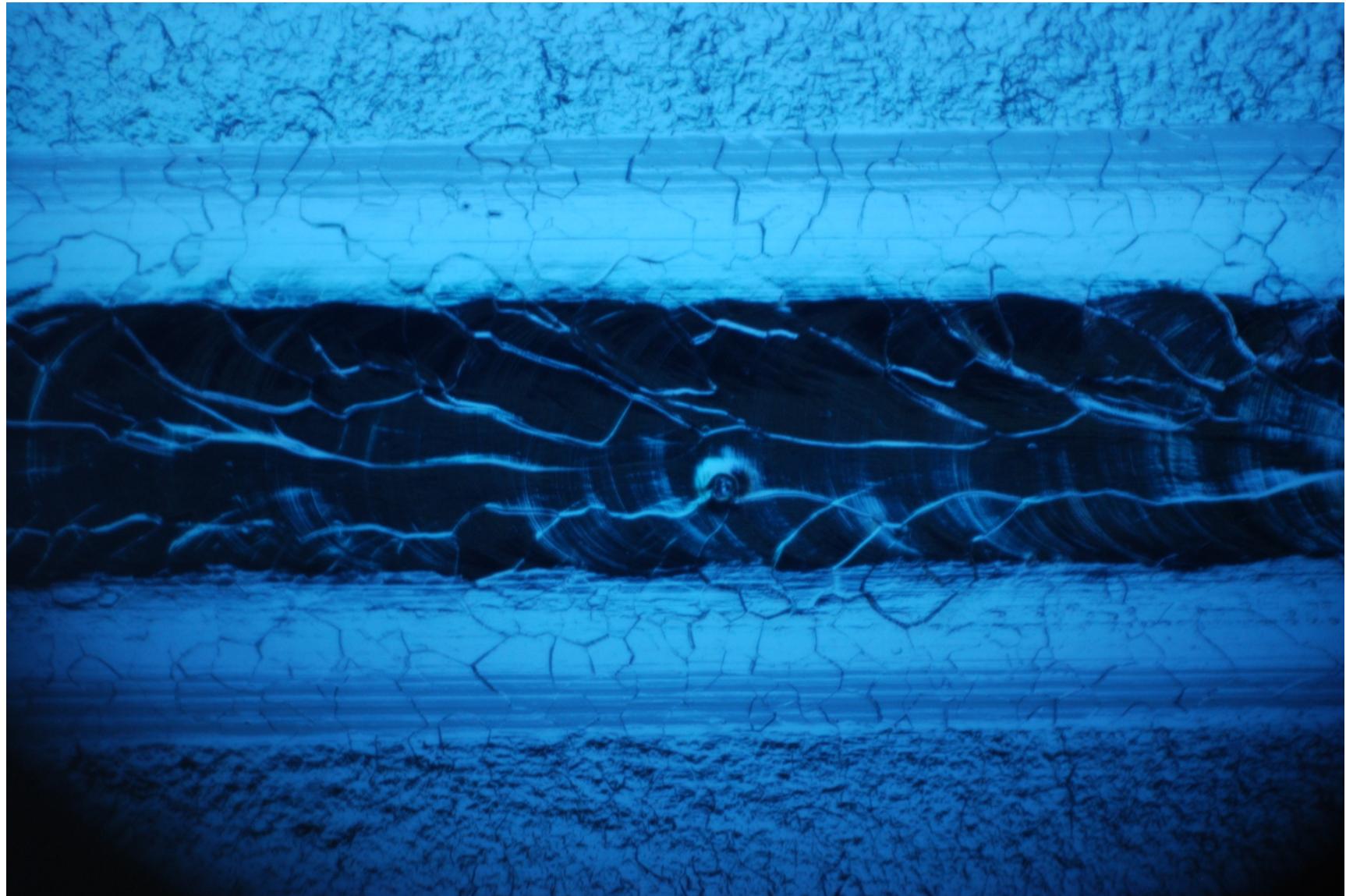
Fine grain EP  
defect causing  
Quench 20 MV/m.

Cavity by then  
new vendor

# Fine grain EP defect causing Quench 15 MV/m. Cavity by then new vendor







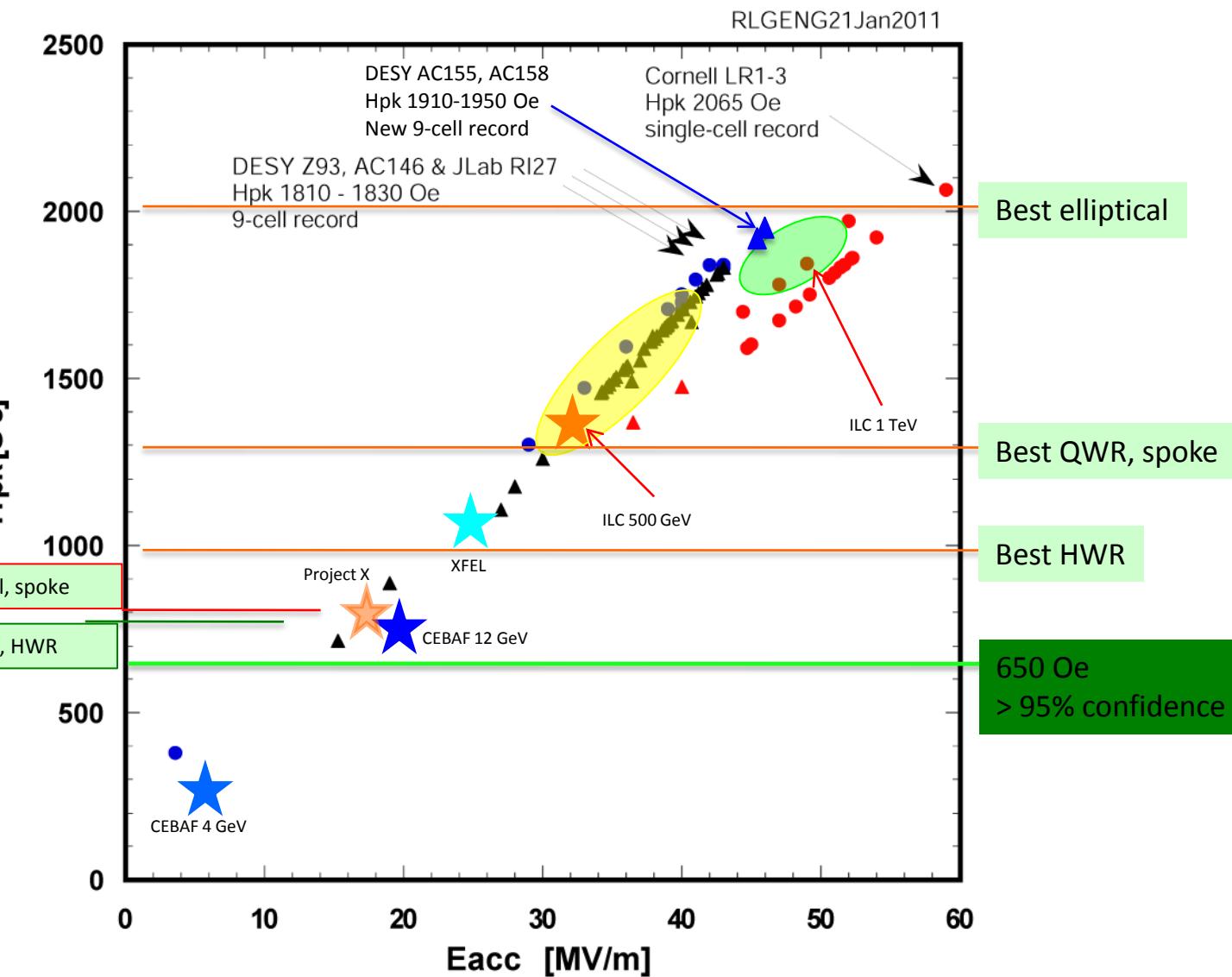
# Type I Defect

- Sub-mm sized geometrical defect at or near EBW joint
  - Independent of manufacturer
    - Experienced or new
  - Independent of surface processing
    - BCP or EP
  - Independent of material
    - Fine-grain or large-grain

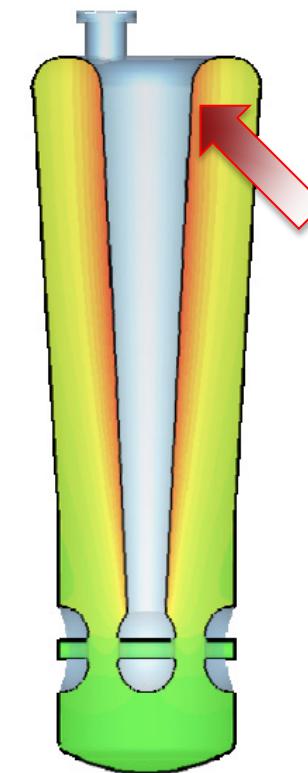
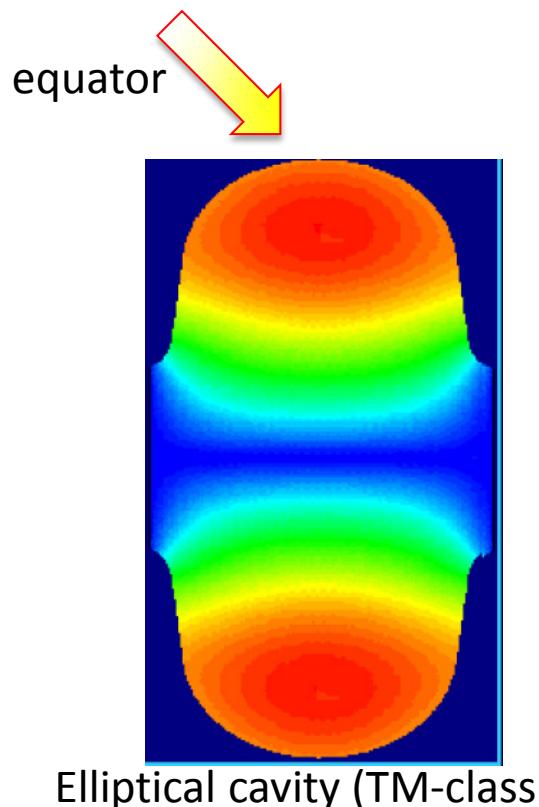
# Sources of Type I Defect

- Fabrication (Electron Beam Welding)
  - Surface defects
    - Optical inspection
    - Mechanical polishing
  - Under-surface defects
    - Pocket/porosity
    - Ultrasonic/X-ray inspection
    - Re-melting
- Material?

Achieved Peak Surface Magnetic Field in L-band SRF Niobium Cavities  
(Circle: Single-Cell Cavity; Triangle: Multi-Cell Cavity)

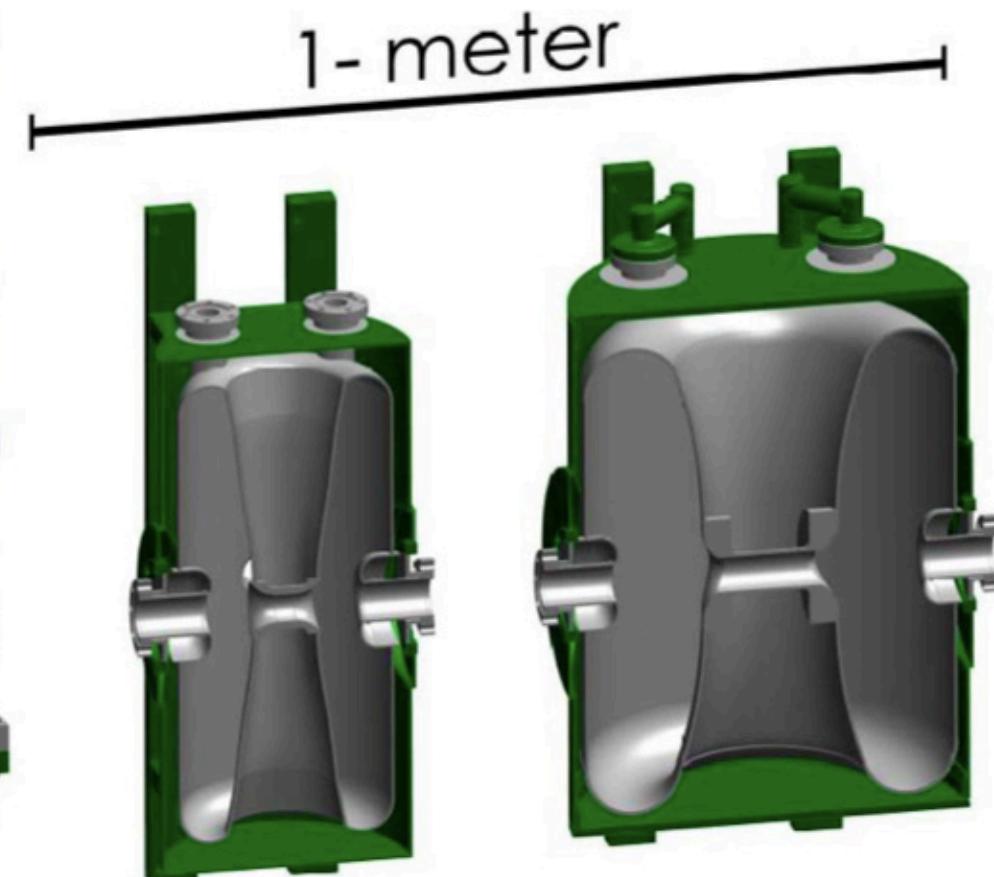


- Quench is primarily a magnetic field effect
  - High magnetic field region (arrow) in cavity is critical



 $\beta = 0.041$  $\beta = 0.085$ 

Facility for Rare Isotope Beams (FRIB)  
Four cavity types, total 350 cavities  
operation temperature 2 Kelvin

 $\beta = 0.29$  $\beta = 0.53$

# Sources of Type II Defect

- Nature is not clear
  - Size is probably sub-micron
  - Probably has to do with surface composition irregularity
  - Probably has to do with processing
  - Probably has to do with material inhomogeneity
  - ...

# Observation

- Type I defect is an issue of common interest
  - for  $\beta=1$  elliptical cavities (ILC)
  - for  $\beta<1$  elliptical cavities (Px, ESS)
  - for  $\beta<1$  cavities HWR, QWR cavities (FRIB)
- Quench study in elliptical cavities (for ILC) improved understanding of type I defect
- Quench study in  $\beta<1$  QWR, HWR, spoke?
- Fabrication improvement is needed
  - Fabrication is and will be done in industry
  - Feedback between lab and industry

# Observation (continued)

- Type II defect is a unique challenge for very high gradient application such as ILC
- Deeper understanding requires high-resolution localization of quench location and microscopic surface material studies of the quench site
- Understanding is necessary toward the ultimate gradient determined by the RF critical field

# Additional Slides

